Date	User	Film	Recipe	Dep.time	Thickness	JAW EC-400 (Woolam S. E.)		Avg Index	Index+1%	Index -1%	Dep. Rate	Avg.dep. rate	Avg+10%	Avg-10%	HF e.r.	Stress	Avg. Stress	Avg+10%	Avg-10%	LPD (light point defects)		Comment	Mike Silva
01/01/14	User	SiO2	1_SiO2Dep	9sec)	(A)	Index @ 632.8nm	Index @1550nm	Index @ 632.8nm			(nm/min)	(nm/min)	(nm/min)	(nm/min)	(nm/min)	(MPa)	(MPa)	(MPa)	(MPa)	LPD before deposition	LPD after deposition		
			Oxide																				
01/09/14	Bilja	SiO2	Bilja_1_SiO2_dep	900	786.01	1.484	1.474	1.487	1.501	1.472	5.24	5.47	6.02	4.92	309.96	-367.80	-373.45	-410.80	-336.11	57	318	Not many particles	
01/31/14	Bilja	SiO2	Bilja_1_SiO2_dep	900	900.81	1.491	1.496	1.487	1.501	1.472	6.01	5.47	6.02	4.92	415.40	-405.46	-373.45	-410.80	-336.11			LPD not done	
03/19/14	Bilja	SiO2	Bilja_1_SiO2_dep	900	817.71	1.487	1.481	1.487	1.501	1.472	5.45	5.47	6.02	4.92	492.07	-386.65	-373.45	-410.80	-336.11	106	485	Not many particles	
04/09/14	Bilja	SiO2	Bilja_1_SiO2_dep	900	778.72	1.485	1.475	1.487	1.501	1.472	5.19	5.47	6.02	4.92	457.19	-333.90	-373.45	-410.80	-336.11	249	649	No stress photo	

Avg. Thickness	820.81				Avg HF e.r.	418.66	
	Avg. Index	1.487	Avg. Dep.Rate	5.47		Avg Stress	-373.45
	Avg+1%	1.501	Avg+10%	6.02		Avg+10%	-410.80
	Avg-1%	1.472	Avg-10%	4.92		Avg-10%	-336.11